## Notice of References Cited Application/Control No. 10/646,931 Examiner Huy D. Nguyen Applicant(s)/Patent Under Reexamination KO ET AL. Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2002/0022497	02-2002	Kim et al.	455/554
*	В	US-2004/0203615	10-2004	Qu et al.	455/412.1
*	С	US-2004/0203763	10-2004	Tammi, Kalle	455/435.1
*	D	US-2001/0046214	11-2001	Kang, Min-Seok	370/328
*	E	US-2002/0022481	02-2002	Yang, Doo-Yong	455/432
*	F	US-2001/0046860	11-2001	Lee, Dong-Youl	455/426
*	G	US-6,330,442	12-2001	Seppanen, Jorma	455/426.1
*	Ξ	US-6,169,895	01-2001	Buhrmann et al.	455/423
	_	US-			
	٦	US-			
	К	US-			
	L	US-			
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0				·	
	Р					
	Q					
	R		·			
	s					
	Т					

## **NON-PATENT DOCUMENTS**

	_	
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	w	
	x	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.